

THE INVENTION CLAIMED IS:

1. An integrated circuit interconnect comprising:  
a wide top metal line;  
a wide bottom metal line;  
5 a dielectric layer disposed between the wide top and wide bottom metal lines;  
a plurality of vias in the dielectric layer and connecting the wide top and wide bottom  
metal lines including:  
a first via having a width, and  
a second via having a width and spaced more than a width away and less than  
10 four widths away from the first via.
2. The integrated circuit as claimed in claim 1 wherein:  
the second via is spaced from the first via in a direction perpendicular to the length of  
the wide top metal line; and including:  
a third via having a width and spaced more than two widths and less than four  
widths from the first via in a direction parallel to the length of the wide  
top metal line.
3. The integrated circuit as claimed in claim 1 wherein:  
the second via is spaced from the first via in a direction parallel to the length of the  
wide top metal line; and including:  
20 a third via having a width and spaced more than two widths and less than four  
widths from the first via in a direction perpendicular to the wide top  
metal line.
4. The integrated circuit as claimed in claim 1 wherein:  
the dielectric layer has an opening provided therein equidistant from the first and  
25 second vias.
5. The integrated circuit as claimed in claim 4 wherein:  
the opening which has a width equal to the width of the first via.
6. The integrated circuit as claimed in claim 4 wherein:  
the opening has a length greater than twice the width thereof.

7. The integrated circuit as claimed in claim 4 wherein:  
the opening has a length and the length extends perpendicular to the length of the  
wide top metal line.

8. An integrated circuit interconnect comprising:  
a wide top metal line;  
a wide bottom metal line;  
a dielectric layer disposed between the wide top and wide bottom metal lines; and  
a via-sea in the dielectric layer and connecting the wide top and wide bottom metal  
lines including:

a first column of vias having a width, and  
a second column of vias having a width and spaced more than a width away  
and less than four widths away from the first column of vias.

9. The integrated circuit as claimed in claim 8 wherein:  
the second column of vias is spaced from the first column of vias in a direction  
perpendicular to the length of the wide top metal line; and including:  
a first row of vias including a via in the first column of vias having a width  
and spaced more than two widths and less than four widths from the  
first column of vias in a direction parallel to the wide top metal line.

10. The integrated circuit as claimed in claim 8 wherein:  
the second column of vias is spaced from the first column of vias in a direction  
parallel to the length of the wide top metal line; and including:  
a first row of vias including a via in the first column of vias having a width  
and spaced more than two widths and less than four widths from the  
first column of vias in a direction perpendicular to the wide top metal  
line.

11. The integrated circuit as claimed in claim 8 wherein:  
the dielectric layer has an opening provided therein equidistant from the first column  
of vias and the second column of vias.

12. The integrated circuit as claimed in claim 11 wherein:  
the opening has a width equal to the width of the first column of vias.

13. The integrated circuit as claimed in claim 11 wherein:  
the opening has a length greater than twice the width thereof.

14. The integrated circuit as claimed in claim 11 wherein:  
the opening has a length and extends perpendicular to the length of the wide top metal  
line.

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